

# EEE6212

## “Semiconductor Materials”

### Practical Lab Assignment

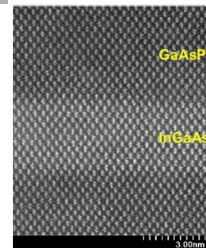
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## Introduction

- Discuss need for characterisation of epitaxial materials
- Focus on combination of photoluminescence and X-Ray diffraction
- Discuss both
- Introduce samples you will study
- How, where, when

# Motivation

- Advanced semiconductor structures are realised via epitaxial processes
- Structures have varying alloy compositions, doping, thickness (mono-layer precision)
- Need methods to characterise deposited materials
- In manufacturing – non-destructive characterisation is required
- PL and X-ray diffraction are a complementary set of methods



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# Photoluminescence (PL)

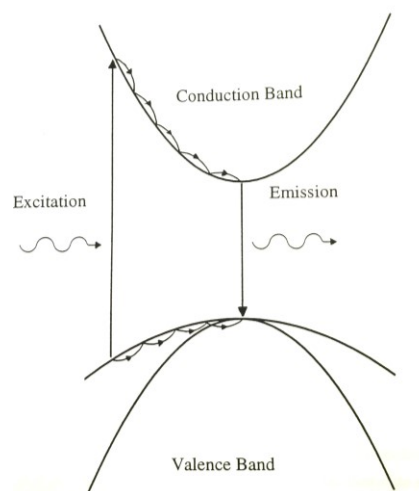
## 3 step process

**Excitation** – above band-gap light creates electrons and holes

**Relaxation** – electron (hole) relaxes to conduction band minimum (valence band maxima)

**Emission** – the electron and hole recombine through spontaneous emission

Provides a direct measure of the band-gap (caveats to this over the page!)



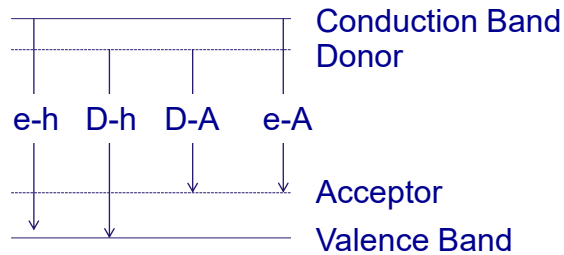
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## PL – Band-gap Caveats.....

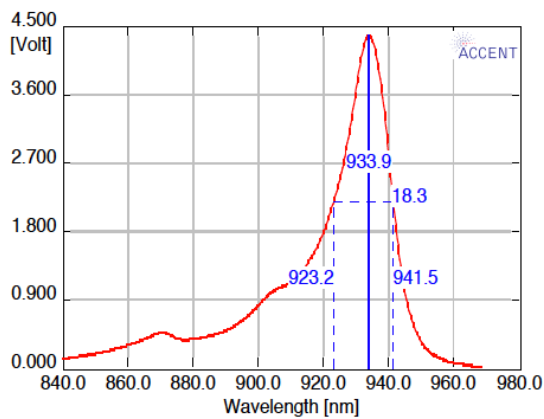
Excitons ? Depending upon the band-gap and the temperature, excitons have a lower energy than the band-gap. At room temperature – not a problem for GaAs, InP.

Donors, Acceptor ?



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## Room Temperature Line-shape



Lineshape is a convolution of Boltzmann Fn and Gaussian

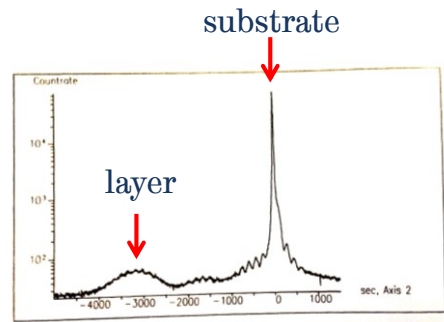
(See <http://dx.doi.org/10.1088/0268-1242/11/1/003>)

Other features from other states (GaAs band-edge, higher order states in QW...)

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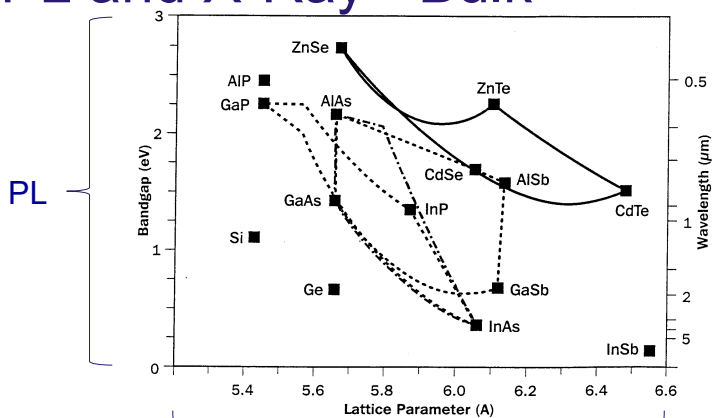
## X-Ray Diffraction – Bulk

- See Lecture 7, XRD tells you many things about the deposited layers
- Critically – can provide a measure of the lattice constants in-plane and out-of plane and thicknesses/periodicities



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## PL and X-Ray - Bulk



### X-Ray Diffraction

(See <http://www.ioffe.ru/SVA/NSM/Semicond/> for lattice parameter and Room Temperature bandgap information)

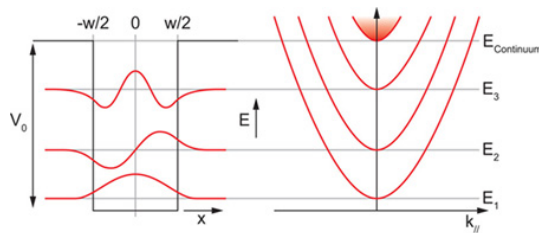
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# The Quantum Well

(We will do this in more detail later...)

QW - Semiconductor structure which creates a potential on the length scale of the De Broglie wavelength of the electron

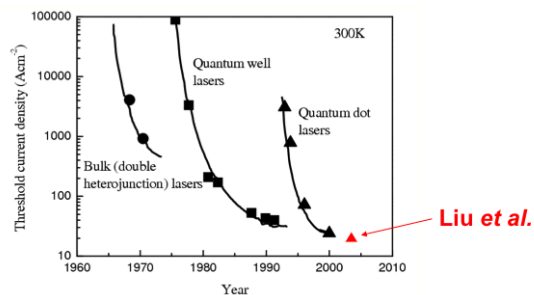
- Lowest energy state no longer from band-edge
- Quantum confinement
- Energy depends upon depth and width of quantum well



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## QW – Why care?

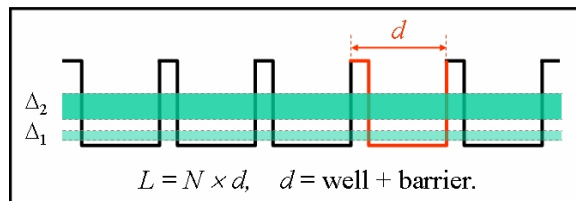
- At the heart of every semiconductor laser
- Many transistors enabled by QWs
- State-of-the-art solar cells...



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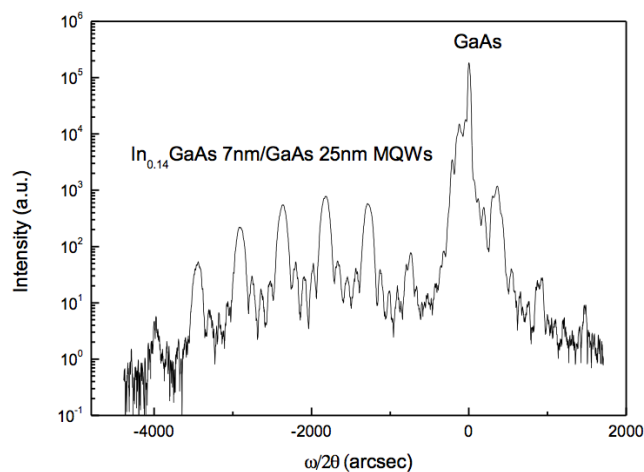
## n.b. The Term “Superlattice”

- Crystallography – multiple layers A/B/A/B.....
- Quantum mechanics – analogous to a crystal lattice – short period quantum well with



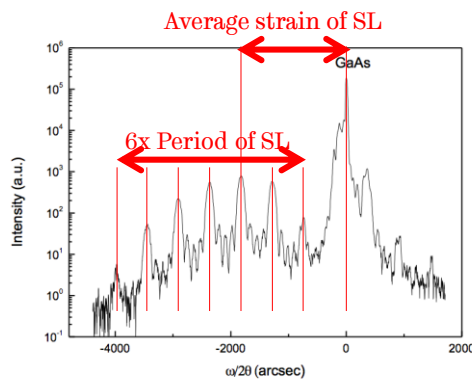
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## Example X-Ray Diffraction



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# Superlattice - X-Ray



**Substrate peak**

**Zero-order peak** – addition of Bragg reflections from A and B components of superlattice. Average composition of A + B layers can be obtained by differentiation of Bragg’s law.

**Satellite peaks** –spacing determined by periodicity of superlattice

(See <http://dx.doi.org/10.1109/COMMAD.2000.1022929> )

# Your Test Samples

## Surface

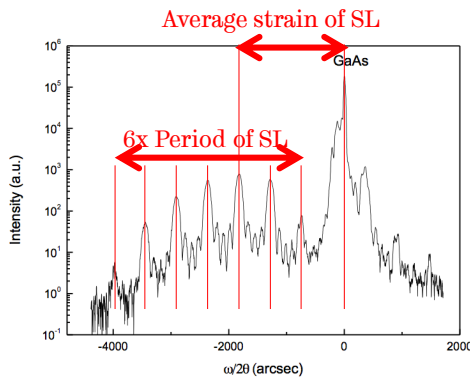
| Repeats | Thickness | Thickness tolerance | Material                                   | Material tolerance | Doping type | Doping level | Doping tolerance |
|---------|-----------|---------------------|--|--------------------|-------------|--------------|------------------|
| 1       | 20.0 nm   |                     | GaAs                                       |                    | Undoped     | 0.0          | cm <sup>-3</sup> |
| 1       | 50.0 nm   |                     | Al <sub>0.3</sub> Ga <sub>0.7</sub> As     |                    | Undoped     | 0.0          | cm <sup>-3</sup> |
| 1       | 25.0 nm   |                     | GaAs                                       |                    | Undoped     | 0.0          | cm <sup>-3</sup> |
| 5       | 25.0 nm   |                     | GaAs                                       |                    | Undoped     | 0.0          | cm <sup>-3</sup> |
| 5       | 8.0 nm    |                     | In <sub>0.125</sub> Ga <sub>0.875</sub> As |                    | Undoped     | 0.0          | cm <sup>-3</sup> |
| 1       | 50.0 nm   |                     | GaAs                                       |                    | Undoped     | 0.0          | cm <sup>-3</sup> |
| 1       | 50.0 nm   |                     | Al <sub>0.3</sub> Ga <sub>0.7</sub> As     |                    | Undoped     | 0.0          |                  |
| 1       | 200.0 nm  |                     | GaAs                                       |                    | Undoped     | 0.0          |                  |
| 1       | 1.0 nm    |                     | -  |                    | Undoped     | 0.0          |                  |

Various [In], thicknesses

## Substrate

Note that it is common in growth sheets for the layer order to be reversed (growth has to start at the substrate and finish at the surface!)

# Your Experiment...



**Substrate peak**

**Satellite peaks** –spacing will change as QW width is varied

**Zero-order peak** – As period changes, so average strain of SL changes

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# What You Will Do

- Before the practical
  - Read all the paperwork and attempt the questions on the sheet
  - The demonstrator may send you home if this is not done satisfactorily!
- Measure X-Ray diffraction curve for your wafers
  - Deduce the period of your superlattice (assumption that GaAs growth rate doesn't change)
  - Deduce the indium composition of your QW
  - Explore reasons for the shape of the curve
- Measure PL spectrum of your wafers
  - Discuss the form of the spectrum
  - Knowing the indium composition, determine the quantum well width
- Write a report
  - Describe background of Molecular Beam Epitaxy, PL measurement, X-Ray diffraction, and your measurements

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## When, Where?

- Experiments will take ~2 hours in the Nano-Science Cleanrooms, North Campus
- |           |               |                    |         |
|-----------|---------------|--------------------|---------|
| Monday    | February 8th  | 3:15 PM – 5:30 PM  | Group 1 |
| Tuesday   | February 9th  | 3:15 PM – 5:30 PM  | Group 2 |
| Wednesday | February 10th | 9:15 AM – 11:30 AM | Group 3 |
| Friday    | February 12th | 11:15 AM – 1:30 PM | Group 4 |
| Monday    | February 15th | 3:15 PM – 5:30 PM  | Group 5 |
| Tuesday   | February 16th | 3:15 PM – 5:30 PM  | Group 6 |
- Check your timetables as soon as possible for any clashes with other module lectures. If so contact me promptly to try and rearrange!!
- DON'T BE LATE**....Be in reception at Centre for Nanoscience and Technology at this time....You are advised not to wear a skirt!

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## How?

- You take the data as a team and have a good long think....
- We will provide a pro-forma template which forms the back-bone of your report and prompt some questions
- You need to describe the experimental procedures, plot graphs (please spend time to do this professionally), process data, draw conclusions and speculate on the interpretation of your data
- The report is worth 25% of the module marks
- Be aware of plagiarism rules and regs.....
- TurnItIn is very efficient.....Don't be a fool....
- .....Good luck!

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## Lectures in Semester 2

- This practical class replaces the EEE6212 lectures for weeks 1 and 2 of Semester 2
- Thus there are **no** EEE6212 lectures on
  - Monday Feb 8<sup>th</sup> 3pm
  - Wednesday Feb 10<sup>th</sup> 1pm
  - Monday Feb 15<sup>th</sup> 3pm
  - Wednesday Feb 17<sup>th</sup> 1pm
- The first EEE6212 lecture of Semester 2 will be on Monday Feb 22<sup>nd</sup> at 3pm (Mappin LT10)

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## Links

<http://dx.doi.org/10.1088/0268-1242/1/1/003>

<http://www.ioffe.ru/SVA/NSM/Semicond/>

<http://dx.doi.org/10.1109/COMMAD.2000.1022929>

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